

**Notice of References Cited**

Application/Control No.

10/506,765

Applicant(s)/Patent Under  
Reexamination  
LI ET AL.

Examiner

Izunna Okeke

Art Unit

4193

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,094,487 A	07-2000	Butler et al.	380/270
*	B	US-2001/0048744 A1	12-2001	Kimura, Shinya	380/247
*	C	US-2002/0090089 A1	07-2002	Branigan et al.	380/270
*	D	US-2002/0120844 A1	08-2002	Faccin et al.	713/168
*	E	US-2003/0048905 A1	03-2003	Gehring et al.	380/270
*	F	US-2003/0112977 A1	06-2003	Ray et al.	380/270
*	G	US-6,853,729 B1	02-2005	Mizikovsky, Semyon B.	380/249
*	H	US-7,003,282 B1	02-2006	Ekberg, Jan-Erik	455/411
*	I	US-7,028,186 B1	04-2006	Stenman et al.	713/173
*	J	US-7,039,190 B1	05-2006	Engwer et al.	380/270
*	K	US-7,107,051 B1	09-2006	Walker, Jesse R.	455/432.1
*	L	US-7,174,564 B1	02-2007	Weatherspoon et al.	726/2
*	M	US-7,310,424 B2	12-2007	Gehring et al.	380/277

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.